Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/731,714	AGASHE ET AL.	
Examiner	Art Unit	•
John P. Trimmings	2138	

	SEAR	CHED	
Class	Subclass	Date	Examiner
			·

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
NPL Search: multple clock domain testing scan chain cores.	4/11/2006	· JPT
Dble Patent Search: Negative.	4/11/2006	JPT
Class Search: 714/25,30,724,725,726, 727,729,730,731,734,735,742,744, 714/819, 702/108, 326/16. Text strategy attached.	4/11/2006	JPT
-		
		: